

* * * * * Welcome to STN International * * * * *

<u>NEWS 1</u>		Web Page URLs for STN Seminar Schedule - N. America
<u>NEWS 2</u>		"Ask CAS" for self-help around the clock
<u>NEWS 3</u>	Feb 24	PCTGEN now available on STN
<u>NEWS 4</u>	Feb 24	TEMA now available on STN
<u>NEWS 5</u>	Feb 26	NTIS now allows simultaneous left and right truncation
<u>NEWS 6</u>	Feb 26	PCTFULL now contains images
<u>NEWS 7</u>	Mar 04	SDI PACKAGE for monthly delivery of multifile SDI results
<u>NEWS 8</u>	Mar 24	PATDPAFULL now available on STN
<u>NEWS 9</u>	Mar 24	Additional information for trade-named substances without structures available in REGISTRY
<u>NEWS 10</u>	Apr 11	Display formats in DGENE enhanced
<u>NEWS 11</u>	Apr 14	MEDLINE Reload
<u>NEWS 12</u>	Apr 17	Polymer searching in REGISTRY enhanced
<u>NEWS 13</u>	SEP 09	CA/CAPLUS records now contain indexing from 1907 to the present
<u>NEWS 14</u>	Apr 21	New current-awareness alert (SDI) frequency in WPIDS/WPINDEX/WPIX
<u>NEWS 15</u>	Apr 28	RDISCLOSURE now available on STN
<u>NEWS 16</u>	May 05	Pharmacokinetic information and systematic chemical names added to PHAR
<u>NEWS 17</u>	May 15	MEDLINE file segment of TOXCENTER reloaded
<u>NEWS 18</u>	May 15	Supporter information for ENCOMPAT and ENCOMPLIT updated
<u>NEWS 19</u>	May 19	Simultaneous left and right truncation added to WSCA
<u>NEWS 20</u>	May 19	RAPRA enhanced with new search field, simultaneous left and right truncation
<u>NEWS 21</u>	Jun 06	Simultaneous left and right truncation added to CBNB
<u>NEWS 22</u>	Jun 06	PASCAL enhanced with additional data
<u>NEWS 23</u>	Jun 20	2003 edition of the FSTA Thesaurus is now available
<u>NEWS 24</u>	Jun 25	HSDB has been reloaded
<u>NEWS 25</u>	Jul 16	Data from 1960-1976 added to RDISCLOSURE
<u>NEWS 26</u>	Jul 21	Identification of STN records implemented
<u>NEWS 27</u>	Jul 21	Polymer class term count added to REGISTRY
<u>NEWS 28</u>	Jul 22	INPADOC: Basic index (/BI) enhanced; Simultaneous Left and Right Truncation available
<u>NEWS 29</u>	AUG 05	New pricing for EUROPATFULL and PCTFULL effective August 1, 2003
<u>NEWS 30</u>	AUG 13	Field Availability (/FA) field enhanced in BEILSTEIN
<u>NEWS 31</u>	AUG 15	PATDPAFULL: one FREE connect hour, per account, in September 2003
<u>NEWS 32</u>	AUG 15	PCTGEN: one FREE connect hour, per account, in September 2003
<u>NEWS 33</u>	AUG 15	RDISCLOSURE: one FREE connect hour, per account, in September 2003
<u>NEWS 34</u>	AUG 15	TEMA: one FREE connect hour, per account, in September 2003
<u>NEWS 35</u>	AUG 18	Data available for download as a PDF in RDISCLOSURE
<u>NEWS 36</u>	AUG 18	Simultaneous left and right truncation added to PASCAL
<u>NEWS 37</u>	AUG 18	FROSTI and KOSMET enhanced with Simultaneous Left and Right Truncation
<u>NEWS 38</u>	AUG 18	Simultaneous left and right truncation added to ANABSTR
<u>NEWS EXPRESS</u>		April 4 CURRENT WINDOWS VERSION IS V6.01a, CURRENT MACINTOSH VERSION IS V6.0b(ENG) AND V6.0Jb(JP), AND CURRENT DISCOVER FILE IS DATED 01 APRIL 2003
<u>NEWS HOURS</u>		STN Operating Hours Plus Help Desk Availability
<u>NEWS INTER</u>		General Internet Information
<u>NEWS LOGIN</u>		Welcome Banner and News Items
<u>NEWS PHONE</u>		Direct Dial and Telecommunication Network Access to STN
<u>NEWS WWW</u>		CAS World Wide Web Site (general information)

Enter NEWS followed by the item number or name to see news on that specific topic.

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* * * * * STN Columbus * * * * *

FILE 'HOME' ENTERED AT 09:44:34 ON 12 SEP 2003

=> file inspec

COST IN U.S. DOLLARS	SINCE FILE ENTRY	TOTAL SESSION
FULL ESTIMATED COST	0.21	0.21

FILE 'INSPEC' ENTERED AT 09:44:53 ON 12 SEP 2003

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FILE LAST UPDATED: 8 SEP 2003 <20030908/UP>

FILE COVERS 1969 TO DATE.

<<< SIMULTANEOUS LEFT AND RIGHT TRUNCATION AVAILABLE IN
THE BASIC INDEX >>>

=> % memory

L1 124328 MEMORY

=> % nanotube

L2 3438 NANOTUBE

=> % l1 and l2

L3 21 L1 AND L2

=> & l3 1-21

L3 ANSWER 1 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	References
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AN 2003:7688442 INSPEC DN A2003-17-8120V-003; B2003-08-0587-018
TI Growth of isolated carbon nanotubes with lithographically defined diameter and location.
AU Duesberg, G.S.; Graham, A.P.; Liebau, M.; Seidel, R.; Unger, E.; Kreupl, F.; Hoenlein, W. (Infineon Technol. AG, Munich, Germany)
SO Nano Letters (Feb. 2003) vol.3, no.2, p.257-9. 17 refs.
Published by: American Chem. Soc
Price: CCCC 1530-6984/03/\$25.00
CODEN: NALEFD ISSN: 1530-6984
SICI: 1530-6984(200302)3:2L.257:GICN;1-7
DT Journal
TC Experimental
CY United States
LA English

L3 ANSWER 2 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	References
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AN 2003:7669655 INSPEC DN B2003-08-1265D-005
TI Concepts for hybrid CMOS-molecular non-volatile memories.
AU Luyken, R.J.; Hofmann, F. (Infineon Technol., Munchen, Germany)
SO Nanotechnology (Feb. 2003) vol.14, no.2, p.273-6. 15 refs.
Doc. No.: S0957-4484(03)53154-3
Published by: IOP Publishing
Price: CCCC 0957-4484/03/020273+04\$30.00

CODEN: NNOTER ISSN: 0957-4484
SICI: 0957-4484(200302)14:2L.273:CHCM;1-T
Conference: Trends in Nanotechnology (TNT 2002) Conference. Santiago de Compostela, Spain, 9-13 Sept 2002

DT Conference Article; Journal
TC General Review
CY United Kingdom
LA English

L3 ANSWER 3 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2003:7615271 INSPEC DN B2003-06-2230F-011
TI **Memory** effect and role of defects in carbon **nanotube** field effect transistors.
AU Johnson, A.T. (Dept. of Phys. & Astron., Pennsylvania Univ., Philadelphia, PA, USA)
SO AIP Conference Proceedings (2002) no.633, p.526-30. 19 refs.
Published by: AIP
Price: CCCC 0094-243X/2002/\$19.00
CODEN: APCPCS ISSN: 0094-243X
SICI: 0094-243X(2002)633L.526:MERD;1-D
DT Journal
TC Practical; Experimental
CY United States
LA English

L3 ANSWER 4 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2003:7582767 INSPEC DN A2003-10-0710C-002; B2003-05-2230F-005
TI A carbon- **nanotube**-based nanorelay.
AU Kinaret, J.M.; Nord, T.; Viefers, S. (Dept. of Appl. Phys., Chalmers Univ. of Technol., Goteborg, Sweden)
SO Applied Physics Letters (24 Feb. 2003) vol.82, no.8, p.1287-9. 21 refs.
Published by: AIP
Price: CCCC 01/03/6951/2003/82(8)/1287(3)/\$19.00
CODEN: APPLAB ISSN: 0003-6951
SICI: 0003-6951(20030224)82:8L.1287:CNBN;1-1
DT Journal
TC Theoretical
CY United States
LA English

L3 ANSWER 5 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2003:7555336 INSPEC DN B2003-04-2230F-004
TI Carbon- **nanotube**-based nonvolatile **memory** with oxide-nitride-oxide film and nanoscale channel.
AU Won Bong Choi; Soodoo Chae; Eunju Bae; Jo-Won Lee (M D Lab., Samsung Adv. Inst. of Technol., Suwon, South Korea); Byoung-Ho Cheong; Jae-Ryoung Kim; Ju-Jin Kim
SO Applied Physics Letters (13 Jan. 2003) vol.82, no.2, p.275-7. 13 refs.
Published by: AIP
Price: CCCC 01/03/6951/2003/82(2)/275(3)/\$19.00
CODEN: APPLAB ISSN: 0003-6951
SICI: 0003-6951(20030113)82:2L.275:CNBN;1-1
DT Journal
TC Practical; Experimental
CY United States
LA English

L3 ANSWER 6 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	CHINA References
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AN 2003:7507209 INSPEC DN B2003-02-1265D-039
 TI A carbon **nanotube**-based random access **memory**.
 AU Sun Jin-peng; Wang Tai-hong (Inst. of Phys., Acad. Sinica, Beijing, China)
 SO Micronanoelectronic Technology (2002) vol.39, no.10, p.8-26. 10 refs.
 Published by: Editorial Board of Micronanoelectronic Technol
 ISSN: 1671-4776
 SICI: 1671-4776(2002)39:10L:8:CNBR;1-K
 DT Journal
 TC Practical; Theoretical
 CY China
 LA Chinese

L3 ANSWER 7 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	CHINA References
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AN 2003:7481698 INSPEC DN B2003-02-2230F-001
 TI Carbon **nanotube memory** devices of high charge storage stability.
 AU Cui, J.B.; Sordan, R.; Burghard, M.; Kern, K. (Max-Planck-Inst. fuer Festkoerperforschung, Stuttgart, Germany)
 SO Applied Physics Letters (21 Oct. 2002) vol.81, no.17, p.3260-2. 20 refs.
 Doc. No.: S0003-6951(02)03042-5
 Published by: AIP
 Price: CCCC 01/03/6951/2002/81(17)/3260(3)/\$19.00
 CODEN: APPLAB ISSN: 0003-6951
 SICI: 0003-6951(20021021)81:17L:3260:CNMD;1-Q
 DT Journal
 TC Practical; Experimental
 CY United States
 LA English

L3 ANSWER 8 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	CHINA References
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AN 2002:7462853 INSPEC DN B2003-01-2230F-008
 TI Concept for a highly scalable nonvolatile **nanotube** based **memory**.
 AU Luyken, R.J.; Hofmann, F. (Corporate Res., Infineon Technol., Munchen, Germany)
 SO AIP Conference Proceedings (2001) no.591, p.581-4. 8 refs.
 Published by: AIP
 Price: CCCC 0094-243X/01/\$18.00
 CODEN: APCPCS ISSN: 0094-243X
 SICI: 0094-243X(2001)591L:581:CHSN;1-M
 Conference: Electronic Properties of Molecular Nanostructures: 15th International Winterschool/Euroconference. Kirchberg, Austria, 3-10 March 2001
 DT Conference Article; Journal
 TC Practical; Experimental
 CY United States
 LA English

L3 ANSWER 9 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	CHINA References
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AN 2002:7458851 INSPEC DN B2003-01-2230F-004
 TI Nonvolatile molecular **memory** elements based on ambipolar **nanotube** field effect transistors.
 AU Radosavljevic, M.; Freitag, M.; Thadani, K.V.; Johnson, A.T. (Dept. of Phys. & Astron., Pennsylvania Univ., USA)
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 Published by: American Chem. Soc
 Price: CCCC 1530-6984/02/\$22.00
 CODEN: NALEFD ISSN: 1530-6984

SICI: 1530-6984(200207)2:7L.761:NMME;1-T
DT Journal
TC Experimental
CY United States
LA English

L3 ANSWER 10 OF 21 INSPEC (C) 2003 IEE on STN

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AN 2002:7458850 INSPEC DN B2003-01-2230F-003
TI High-mobility **nanotube** transistor **memory**.
AU Fuhrer, M.S.; Kim, B.M.; Durkop, T.; Brintlinger, T. (Dept. of Phys., Maryland Univ., College Park, MD, USA)
SO Nano Letters (July 2002) vol.2, no.7, p.755-9. 21 refs.
Published by: American Chem. Soc
Price: CCCC 1530-6984/02/\$22.00
CODEN: NALEFD ISSN: 1530-6984
SICI: 1530-6984(200207)2:7L.755:HMNT;1-I

DT Journal
TC Experimental
CY United States
LA English

L3 ANSWER 11 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Citing References
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AN 2002:7448416 INSPEC DN B2002-12-2230F-006
TI A carbon **nanotube**-based nonvolatile random access **memory**.
AU Sun Jin-Peng; Wang Tai-Hong (Inst. of Phys., Acad. Sinica, Beijing, China)
SO Acta Physica Sinica (2002) vol.51, no.9, p.2096-100. 7 refs.
Published by: Chinese Phys. Soc
CODEN: WLHPAR ISSN: 1000-3290
SICI: 1000-3290(2002)51:9L.2096:CNBN;1-A

DT Journal
TC Theoretical
CY China
LA Chinese

L3 ANSWER 12 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Citing References
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AN 2002:7447571 INSPEC DN A2002-24-0710C-008; B2002-12-2575-019
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AU Spinks, G.M.; Wallace, G.G. (Intelligent Polymer Res. Inst., Wollongong Univ., NSW, Australia); Fifield, L.S.; Dalton, L.R.; Mazzoldi, A.; De Rossi, D.; Khayrullin, I.I.; Baughman, R.H.
SO Making Functional Materials with Nanotubes. Symposium (Materials Research Society Symposium Proceedings Vol.706)
Editor(s): Bernier, P.; Ajayan, P.; Iwasa, Y.; Nikolaev, P.
Warrendale, PA, USA: Mater. Res. Soc, 2002. p.301-6 of xiii+388 pp. 9 refs.
Conference: Boston, MA, USA, 26-29 Nov 2001
ISBN: 1-55899-642-7

DT Conference Article
TC Experimental; Practical
CY United States
LA English

L3 ANSWER 13 OF 21 INSPEC (C) 2003 IEE on STN

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AN 2002:7439296 INSPEC DN B2002-12-2230-008
TI Molecular-scale engineering for future electronics.
AU Tsui, R.

SO 2002 IEEE International Symposium on Circuits and Systems. Proceedings
(Cat. No.02CH37353)
Piscataway, NJ, USA: IEEE, 2002. p.II-41 vol.2 of 5
vol.(cxxi+924+886+898+889+871) pp.
Conference: Phoenix-Scottsdale, AZ, USA, 26-29 May 2002
Sponsor(s): IEEE; IEEE Circuits & Syst. Soc
Price: CCCC 0-7803-7448-7/02/\$17.00
ISBN: 0-7803-7448-7
DT Conference Article
TC General Review
CY United States
LA English

L3 ANSWER 14 OF 21 INSPEC (C) 2003 IEE on STN

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AN 2002:7407347 INSPEC DN A2002-22-8120V-016; B2002-11-0587-020
TI Applications of carbon nanotubes to electron emitters.
AU Young Hee Lee; Seong Chu Lim; Kay Hyeok An; Won Seok Kim; Hee Jin Jeong;
Young Min Shin (Nat. Res. Lab. for Carbon Nanotubes, Sung Kyun Kwan Univ.,
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SO New Diamond and Frontier Carbon Technology (2002) vol.12, no.4, p.181-207.
51 refs.
Published by: MYU
CODEN: NDFTFF ISSN: 1344-9931
SICI: 1344-9931(2002)12:4L:181:ACNE;1-K
Conference: 6th Applied Diamond Conference/2nd Frontier Carbon Technology
Joint Conference. Auburn, AL, USA, Aug 2001
DT Conference Article; Journal
TC Application; Bibliography; Experimental
CY Japan
LA English

L3 ANSWER 15 OF 21 INSPEC (C) 2003 IEE on STN

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AN 2002:7380161 INSPEC DN B2002-10-2230F-013
TI Charge transfer control by gate voltage in crossed **nanotube** junction.
AU Yoneya, N. (RIKEN, Saitama, Japan); Tsukagoshi, K.; Aoyagi, Y.
SO Applied Physics Letters (16 Sept. 2002) vol.81, no.12, p.2250-2. 15 refs.
Doc. No.: S0003-6951(02)04437-6
Published by: AIP
Price: CCCC 0003-6951/2002/81(12)/2250(3)/\$19.00
CODEN: APPLAB ISSN: 0003-6951
SICI: 0003-6951(20020916)81:12L:2250:CTCG;1-O
DT Journal
TC Experimental
CY United States
LA English

L3 ANSWER 16 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	References
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AN 2002:7340656 INSPEC DN B2002-09-2550N-012
TI Nanotechnology goals and challenges for electronic applications.
AU Bohr, M.T. (Intel Corp., Hillsboro, OR, USA)
SO IEEE Transactions on Nanotechnology (March 2002) vol.1, no.1, p.56-62. 62
refs.
Doc. No.: S1536-125X(02)04586-6
Published by: IEEE
Price: CCCC 1536-125X/02/\$17.00
CODEN: ITNECU ISSN: 1536-125X
SICI: 1536-125X(200203)1:1L:56:NGCE;1-J
DT Journal

TC Application; Bibliography; General Review
CY United States
LA English

L3 ANSWER 17 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2002:7252241 INSPEC DN A2002-11-7125X-006; B2002-06-0587-002
TI Bandgap modulation of carbon nanotubes by encapsulated metallofullerenes.
AU Jhinwan Lee; Kim, H. (Sch. of Phys., Seoul Nat. Univ., South Korea);
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T.; Shinohara, H.; Young Kuk, Y.
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Published by: Nature Publishing Group
Price: CCCC 0028-0836/02/\$12.00+2.00
CODEN: NATUAS ISSN: 0028-0836
SICI: 0028-0836(20020228)415:6875L.1005:BMCN;1-H
DT Journal
TC Experimental
CY United Kingdom
LA English

L3 ANSWER 18 OF 21 INSPEC (C) 2003 IEE on STN

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AN 2002:7136481 INSPEC DN B2002-02-1265B-015
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AU Bachtold, A.; Hadley, P.; Nakanishi, T.; Dekker, C. (Dept. of Appl. Phys.,
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Published by: American Assoc. Adv. Sci
Price: CCCC 0036-8075/01/\$8.00
CODEN: SCIEAS ISSN: 0036-8075
SICI: 0036-8075(20011109)294:5545L.1317:LCWC;1-G
DT Journal
TC Practical; Experimental
CY United States
LA English

L3 ANSWER 19 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2001:6937088 INSPEC DN A2001-13-4265-005
TI Observation of self-diffraction by gratings in nematic liquid crystals
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AU Wei Lee; Chi-Shen Chiu (Dept. of Phys., Chung Yuan Christian Univ., Chung
Li, Taiwan)
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Published by: Opt. Soc. America
CODEN: OPLEDP ISSN: 0146-9592
SICI: 0146-9592(20010415)26:8L.521:OSDG;1-8
DT Journal
TC Theoretical; Experimental
CY United States
LA English

L3 ANSWER 20 OF 21 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2000:6702451 INSPEC DN B2000-10-2230F-003; C2000-10-5320Z-001
TI Carbon **nanotube**-based nonvolatile random access **memory** for molecular
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AU Rueckes, T. (Dept. of Chem., Harvard Univ., Cambridge, MA, USA); Kim, K.;
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 Published by: American Assoc. Adv. Sci
 Price: CCCC 0036-8075/2000/\$8.00
 CODEN: SCIEAS ISSN: 0036-8075
 SICI: 0036-8075(20000707)289:5476L.94:CNBN;1-G
 DT Journal
 TC Theoretical; Experimental
 CY United States
 LA English

L3 ANSWER 21 OF 21 INSPEC (C) 2003 IEE on STN



AN 2000:6504820 INSPEC DN B2000-03-2230F-007
 TI The potential of carbon-based **memory** systems.
 AU Brehob, M.; Enbody, R.; Young-Kyun Kwon; Tomanek, D. (Dept. of Comput.
 Sci. & Eng., Michigan State Univ., East Lansing, MI, USA)
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 Editor(s): Rajsuman, R.; Wik, T.
 Los Alamitos, CA, USA: IEEE Comput. Soc, 1999. p.110-14 of ix+131 pp. 7
 refs.
 Conference: San Jose, CA, USA, 9-10 Aug 1999
 Sponsor(s): IEEE Comput. Soc.; IEEE Comput. Soc. Tech. Committee on VLSI;
 IEEE Comput. Soc. Techno. Council on Test Technol
 Price: CCCC 0 7695 0259 8/99/\$10.00
 ISBN: 0-7695-0259-8
 DT Conference Article
 TC General Review; Theoretical
 CY United States
 LA English

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